

Resource Summary Report

Generated by [SPARC SAWG](#) on Aug 10, 2026

FEI: Verios 5 XHR SEM

RRID:SCR_019914

Type: Tool

Proper Citation

FEI: Verios 5 XHR SEM (RRID:SCR_019914)

Resource Information

URL: <https://www.fei.com/products/sem/Verios-G4-XHR-SEM-for-Materials-Science/>

Proper Citation: FEI: Verios 5 XHR SEM (RRID:SCR_019914)

Description: Microscope that is used for characterization of nanomaterials with sub nanometer resolution and high material contrast SEM.

Resource Type: instrument resource

Keywords: FEI, SEM, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Verios 5 XHR SEM

Resource ID: SCR_019914

Alternate IDs: Model_Number_Verios 5

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260808T190143+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Verios 5 XHR SEM.

No alerts have been found for FEI: Verios 5 XHR SEM.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.